

P A T E N T

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Application of:

Shigeo Kittaka et al.

Serial No.: 10/623,448

Examiner: Unknown

Filed: July 18, 2003

Group Art Unit: 2877

For: DIFFRACTION DEVICE USING PHOTONIC CRYSTAL

Docket No.: 1018.1177101



INFORMATION DISCLOSURE STATEMENT

CERTIFICATE UNDER 37 C.F.R. § 1.10: The undersigned hereby certifies that this paper or papers, as described herein, are being deposited in the United States Postal Service, "Express Mail Post Office to Address", having an Express Mail mailing label number of: EV 333854169 US, in an envelope addressed to: Mail Stop Missing Parts, Commissioner for Patents, PO Box 1450, Alexandria, VA 22313-1450 on this 28th day of October 2003.

By Kathleen L. Boekley
Kathleen L. Boekley

Dear Sir:

Pursuant to the obligations of candor and good faith imposed by 37 C.F.R. § 1.56, the documents listed on the attached PTO-1449 are hereby disclosed.

No representation is intended to be made hereby that any of the cited references establishes, by itself or in combination with other information, a prima facie case of unpatentability of any claim of the present case.

Respectfully submitted,

Shigeo Kittaka et al.

By their Attorney,

David M. Crompton
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FORM PTO-1449 	Atty. Docket No.: 1018.1177101	Serial No.: 10/623,448
	Applicant: Shigeo Kittaka et al.	
	Filing Date: July 18, 2003	Group Art: 2877

U.S. PATENT DOCUMENTS				
Examiner Initial	Document No.	Date	Name	Filing Date If Appropriate

FOREIGN PATENT DOCUMENTS				
	Document No.	Date	Country	Translation Yes No
AA	JP 2002-174740 A	06/21/2002	Japan	Yes

OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)	
AB	Miura, Toru et al., "Propagation Characteristics of Hollow Optical Waveguide for Temperature-Insensitive Photonic Integrated Circuits," 8 th Microoptics Conference (MOC '01), Osaka, Japan, October 24-26, 2001, pp. 52-55.

EXAMINER:	DATE CONSIDERED:
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.